Search Notes	Application/Control No. 10632499	Applicant(s)/Patent Under Reexamination OLSCHEWSKI, FRANK
	Examiner Dennis Rosario	Art Unit 2624

SEARCHED

Class	Subclass	Date	Examiner
382	103	3/6/08	DR
348	169	3/6/08	DR
382	103 updated	9/2/08	DR
		3/24/09	DR
345	181	3/24/09	DR
348	169-172, 208.14	3/24/09	DR
359	383	3/24/09	DR
396	51	3/24/09	DR
382	107	10/2/2009	DR

SEARCH NOTES

Search Notes	Date	Examiner
East, all dB	3/6/08	DR
ACM-+microscope +trajectory +vector-	3/6/08	DR
IEEE-((((microscope)<in>metadata)<and>((track*)<in>metadata))<and>((vector)<in>metadata))-	3/6/08	DR
East, all db, updated	9/2/08	DR
IEEE-((trajector* <near/5> pixel)<in>metadata)-	9/2/08	DR
East, all db	3/24/09	DR
Google Scholar-trajectory pixel vector field-	3/24/09	DR
East, all db	10/2/2009	DR
Google Scholar-displacement vector field microscope-	10/2/2009	DR

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner